

IPS118N10N G-VB Datasheet N-Channel 100-V (D-S), 175 °C MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
100	0.0125 at V _{GS} = 10 V	65	48 nC			

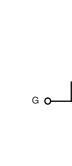
FEATURES

- Trench Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested



APPLICATIONS

- · Primary Side Switch
- Isolated DC/DC Converter



N-Channel MOSFET

T	0-25	1	
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	0		
			Drain Connected to Drain-Tab
G	D	S	
To	p Vie	W	

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V_{DS}	100	V	
Gate-Source Voltage		V_{GS}	± 20	v	
	T _C = 25 °C		65 ^a		
Continuous Drain Current (T. 150 °C)	T _C = 100 °C		52		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	8.2 ^b		
	T _A = 100 °C		5.8 ^b		
Pulsed Drain Current	I _{DM}	200	A		
Continuous Source-Drain Diode Current	T _C = 25 °C		65 ^a		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.0 ^b		
Single Pulse Avalanche Current L = 0.1 mH		I _{AS}	48		
Avalanche Energy	L = U. I IIII	E _{AS}	121	mJ	
	T _C = 25 °C		156.4		
Maximum Power Dissipation	T _C = 100 °C	ь	78.2	w	
	T _A = 25 °C	P _D	3.0 ^b	VV	
	T _A = 100 °C		1.5 ^b		
Operating Junction and Storage Temperature Ra	T _J , T _{stq}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^b	Steady State	R_{thJA}	40	50	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	0.85	1.1	C/VV		

Notes:

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.



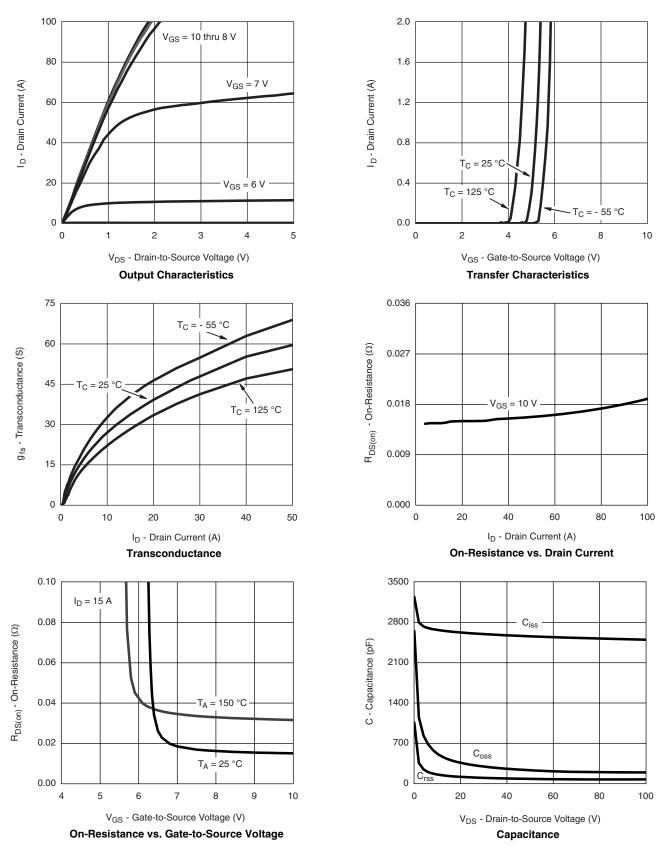
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$	100			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			110			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 12.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	l	V _{DS} = 100 V, V _{GS} = 0 V			1		
Zeio Gate voltage Diaili Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 125 °C			50	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	50			Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$		0.0125		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 15 A		33		S	
Dynamic ^b							
Input Capacitance	C _{iss}			2800		pF	
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		260			
Reverse Transfer Capacitance	C _{rss}			100			
Total Gate Charge	Qg			48	75	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 50 \text{ A}$		16			
Gate-Drain Charge	Q _{gd}			13			
Gate Resistance	R_g	f = 1 MHz		1.6	2.5	Ω	
Turn-On Delay Time	t _{d(on)}			12	20		
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_{L} = 1.0 \Omega$		10	20	ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 50 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		18	35		
Fall Time	t _f			8	15		
Drain-Source Body Diode Characteris	tics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			50	^	
Pulse Diode Forward Current ^a	I _{SM}				100	_ A	
Body Diode Voltage	V _{SD}	I _S = 15 A		0.85	1.5	V	
Body Diode Reverse Recovery Time	t _{rr}			80	120	ns	
Body Diode Reverse Recovery Charge Q		L = 50 A dl/dt = 100 A/up T = 05 °C		160	240	nC	
Reverse Recovery Fall Time	t _a	$I_F = 50 \text{ A}, \text{ dI/dt} = 100 \text{ A/µs}, T_J = 25 ^{\circ}\text{C}$		57		ns	
Reverse Recovery Rise Time	t _b			23		ns	

Notes:

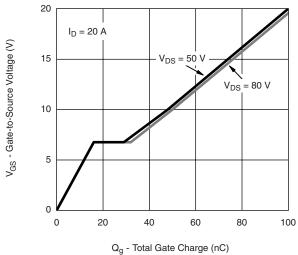
- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

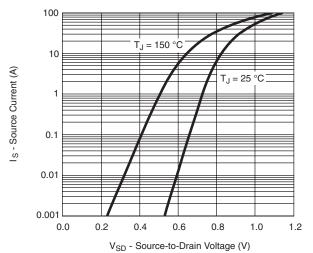




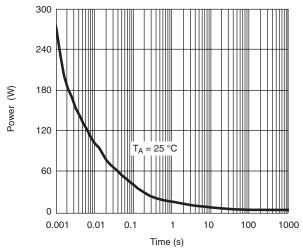




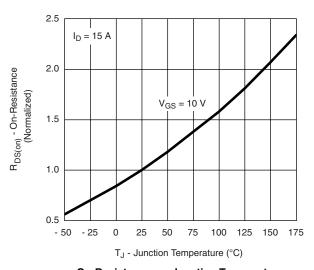




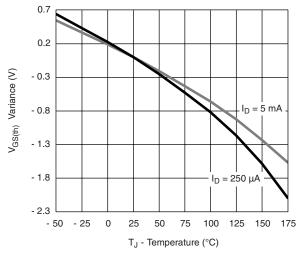
Source-Drain Diode Forward Voltage



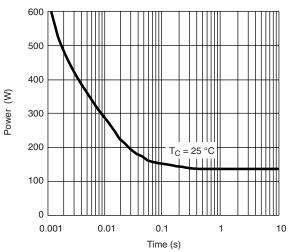
Single Pulse Power, Junction-to-Ambient



On-Resistance vs. Junction Temperature

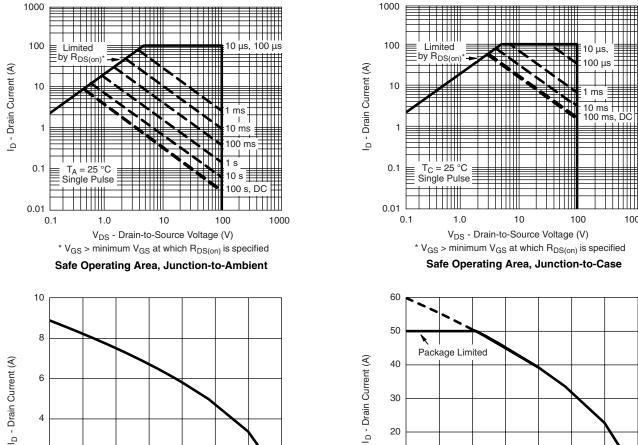


Threshold Voltage



Single Pulse Power, Junction-to-Case





T_A - Ambient Temperature (°C) Current Derating**, Junction-to-Ambient

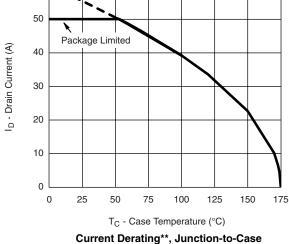
100

125

150

175

75



^{**} The power dissipation P_D is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

服务热线:400-655-8788

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0 0

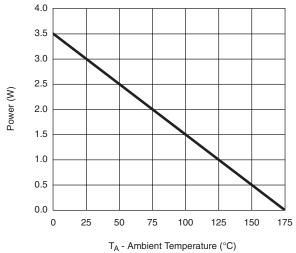
25

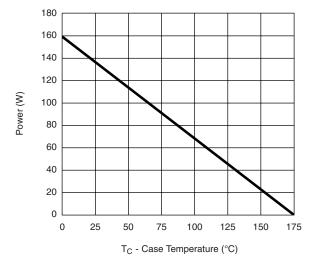
50

6



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



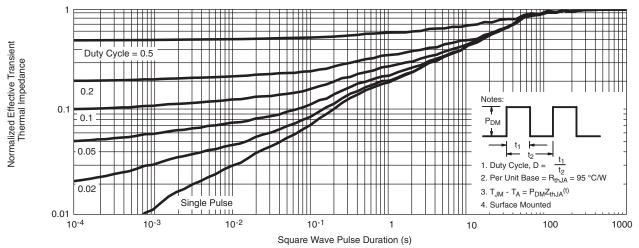


Power Derating*, Junction-to-Ambient

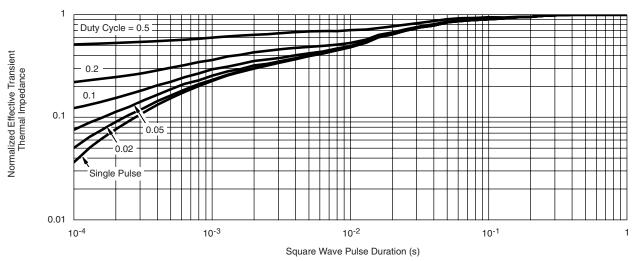
Power Derating*, Junction-to-Case

^{*} The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





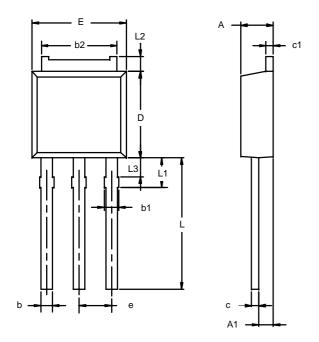
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



TO-251AA (DPAK)



	Note:	Dimension	L3 is for	reference only.
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	MILLIMETERS		INC	HES
Dim	Min	Max	Min	Max
Α	2.21	2.38	0.087	0.094
A1	0.89	1.14	0.035	0.045
b	0.71	0.89	0.028	0.035
b1	0.76	1.14	0.030	0.045
b2	5.23	5.43	0.206	0.214
С	0.46	0.58	0.018	0.023
с1	0.46	0.58	0.018	0.023
D	5.97	6.22	0.235	0.245
Е	6.48	6.73	0.255	0.265
е	2.28 BSC		0.090 BSC	
L	3.89	9.53	0.153	0.375
L1	1.91	2.28	0.075	0.090
L2	0.89	1.27	0.035	0.050
L3	1.15	1.52	0.045	0.060



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